

February 2010 UniFET-IITM

FDP8N50NZF / FDPF8N50NZF N-Channel MOSFET

500V, **7A**, **1** Ω

Features

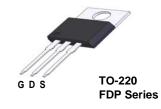
- $R_{DS(on)} = 0.85\Omega$ (Typ.) @ $V_{GS} = 10V$, $I_D = 3.25A$
- Low Gate Charge (Typ. 14nC)
- Low C_{rss} (Typ. 5pF)
- · Fast Switching
- 100% Avalanche Tested
- Improve dv/dt Capability
- · ESD Improved Capability
- · RoHS Compliant



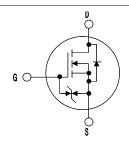
Description

This N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.







MOSFET Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol		Parameter			FDPF8N50NZF	Units
V _{DSS}	Drain to Source Voltage			;	V	
V _{GSS}	Gate to Source Voltage			:	±25	V
	Drain Current	-Continuous (T _C = 25°C)		7	7*	۸
'D	Diam Current	-Continuous (T _C = 100°C)		4.2	4.2*	Α
I _{DM}	Drain Current - Pulsed (Note		(Note 1)	28 28*		Α
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	93		mJ
I _{AR}	Avalanche Current		(Note 1)	7		Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	13		mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	15		V/ns
Б	Power Dissipation	$(T_C = 25^{\circ}C)$		130	40	W
P_{D}	- Derate above 25°C		1	0.32	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range			-55	to +150	°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			;	300	°C

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FDP8N50NZF	FDPF8N50NZF	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.96	3.1	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

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Units

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP8N50NZF	FDP8N50NZF	TO-220	-	-	50
FDPF8N50NF	FDPF8N50NZF	TO-220F	-	-	50

Test Conditions

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted Parameter

Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$, $V_{GS} = 0 V$, $T_C = 25 ^{\circ} C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.5	-	V/°C
1	Zero Gate Voltage Drain Current	$V_{DS} = 500V, V_{GS} = 0V$	-	-	10	
I _{DSS} Zero Gate Voltage Drain Current	$V_{DS} = 400V, T_{C} = 125^{\circ}C$	-	-	100	μА	
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$	-	-	±10	μА

On Characteristics

Symbol

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 3.5A$	-	0.85	1	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 20V, I_D = 3.5A$ (Note 4)	-	6.3	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 25V V 20V	-	565	735	pF
C _{oss}	Output Capacitance	V _{DS} = 25V, V _{GS} = 0V - f = 1MHz		80	105	pF
C _{rss}	Reverse Transfer Capacitance	1 - 10012		5	8	pF
Q _{g(tot)}	Total Gate Charge at 10V		-	14	18	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 7A$	-	4	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V (Note 4, 5)	-	6	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		-	17	45	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_{D} = 7A$	-	34	80	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25\Omega$, $V_{GS} = 10V$	-	43	95	ns
t _f	Turn-Off Fall Time	(Note 4, 5)	-	27	60	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current			-	-	7	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	-	28	Α
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0V$, $I_{SD} = 7A$		-	-	1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0V$, $I_{SD} = 7A$		-	80	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	0.3	-	μС

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 3.8mH, I_{AS} = 7A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}C$ 3. $I_{SD} \le 7A$, $di/dt \le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- 4. Pulse Test: Pulse width $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

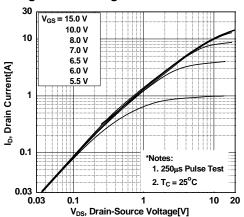


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

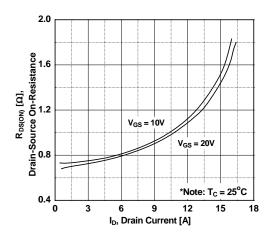


Figure 5. Capacitance Characteristics

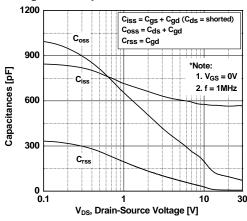


Figure 2. Transfer Characteristics

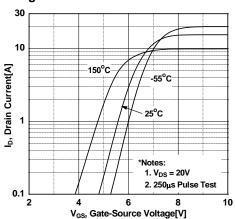


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

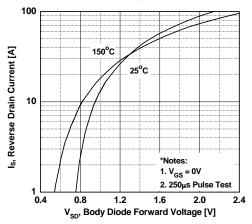
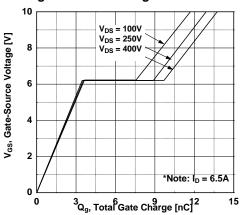


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

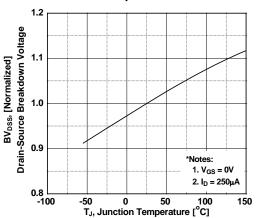


Figure 8. Maximum Safe Operating Area - FDPF8N50NZF

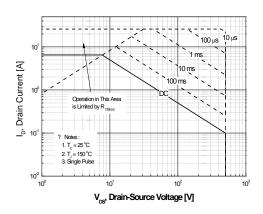


Figure 9. Maximum Drain Current vs. Case Temperature

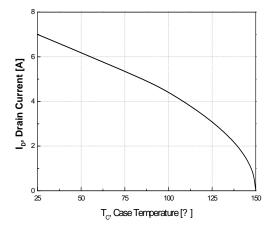
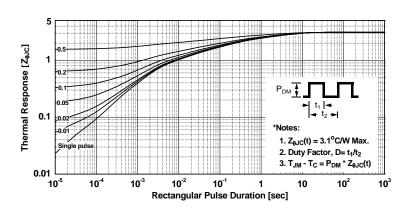


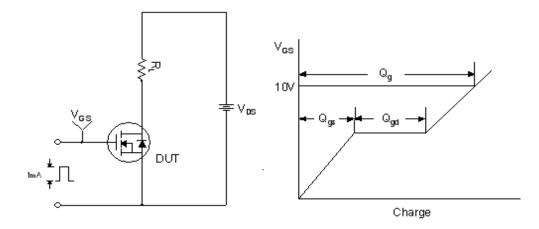
Figure 11. Transient Thermal Response Curve -FDPF8N50NZF



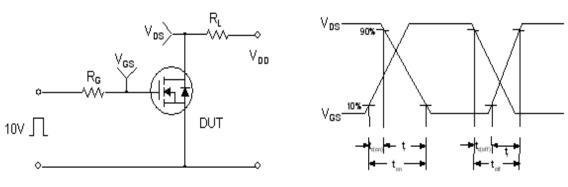
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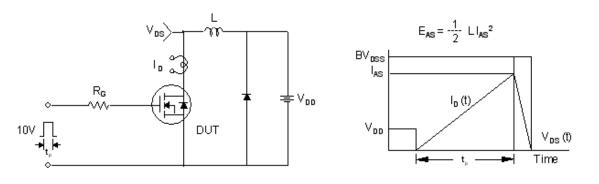
Gate Charge Test Circuit & Waveform



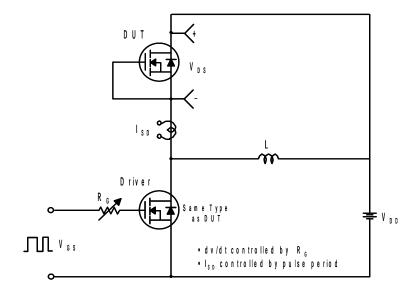
Resistive Switching Test Circuit & Waveforms



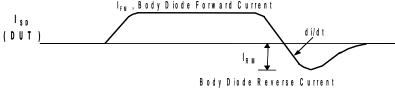
Unclamped Inductive Switching Test Circuit & Waveforms

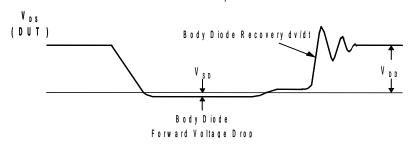


Peak Diode Recovery dv/dt Test Circuit & Waveforms



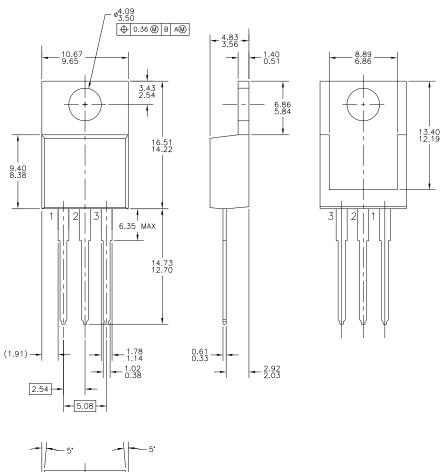


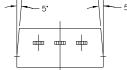




Mechanical Dimensions

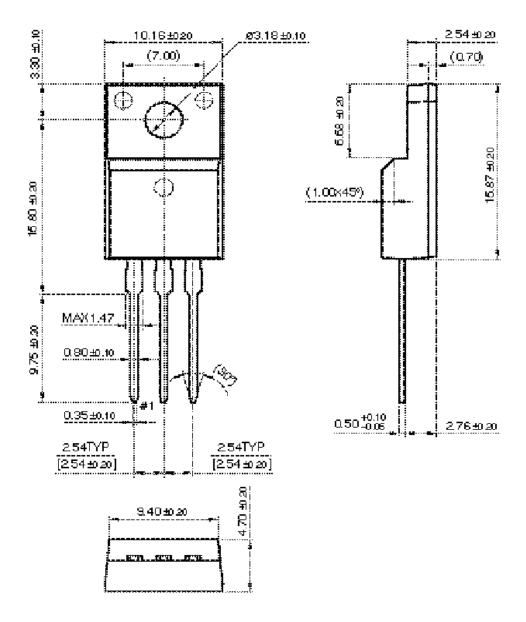
TO-220





Package Dimensions

TO-220F Potted



* Front/Back Side Isolation Voltage : AC 2500V

Dimensions in Millimeters





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